The embodiments of the invention in which an exclusive property or privilege is claimed are defined as follows:

1. An apparatus for indicating real time focus in a scanning microscope, the apparatus comprising:

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a detector for detecting an electrical signal from the scanning microscope; one or more bandpass filters for filtering the detected electrical signal, wherein the one or more bandpass filters are tuned to a desired range of frequencies; and

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one or more power indicators for detecting and displaying average power of the filtered electrical signal of a corresponding bandpass filter.

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- 2. The apparatus of Claim 1, wherein the one or more bandpass filters comprises at least one of a low, medium, or high pass filter.
- 3. The apparatus of Claim 1, further comprising a focusing device for generating a focusing signal based on the detected average power and focusing the scanning microscope based on the generated focusing signal.
- 4. The apparatus of Claim 3, wherein the focusing device automatically performs generating and focusing.
- 5. The apparatus of Claim 1, wherein the scanning microscope is a confocal microscope.
- 6. A method for indicating real time focus in a scanning microscope, the method comprising:

detecting an electrical signal from the scanning microscope;

filtering the detected electrical signal according one or more frequency ranges; and

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detecting average power of the filtered electrical signal for each of the one or more frequency ranges; and

displaying each of the detected average powers of the electrical signal.

- 7. The method of Claim 6, wherein filtering is performed by one or more bandpass filters.
- 30 8. The method of Claim 7, wherein the one or more bandpass filters comprises at least one of a low, medium, or high pass filter.
 - 9. The method of Claim 6, further comprising:



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generating a focusing signal based on the detected average power; and focusing the scanning microscope based on the generated focusing signal.

- 10. The method of Claim 9, wherein focusing comprises automatically focusing.
- 11. The method of Claim 6, wherein the scanning microscope is a confocal 5 microscope.
 - 12. An apparatus for indicating real time focus in a scanning microscope, the apparatus comprising:

a detector for detecting an electrical signal from the scanning microscope; one or more bandpass filters for filtering the detected electrical signal, wherein the one or more bandpass filters are tuned to a desired range of frequencies; and

- a focusing device for generating a focusing signal based on the filtered electrical signal and focusing the scanning microscope based on the generated focusing signal.
- 13. The apparatus of Claim 12, wherein the focusing device automatically performs generating and focusing.

